Appl. No. Unassigned; Docket No. NL03 1167 US Amdt. dated February 6, 2006 Preliminary Amendment

## Amendments to the Specification

Please amend the Abstract as follows.

The present invention provides a method of manufacturing on a substrate (50) a 2-transistor memory cell comprising a storage transistor (1) having a memory gate stack (1) and a selecting transistor, there being a tunnel dielectric layer (51) between the substrate (50) and the memory gate stack (1). The method comprises forming the memory gate stack (1) by providing a first conductive layer (52) and a second conductive layer (54) and etching the second conductive layer (54) thus forming a control gate and etching the first conductive layer (52) thus forming a floating gate. The method is characterized in that it comprises, before etching the first conductive layer (52), forming spacers (81) against the control gate in the direction of a channel to be formed under the tunnel dielectric layer (51), and thereafter using the spacers (81) as a hard mask to etch the first conductive layer (52) thus forming the floating gate, thus making the floating gate self aligned with the control gate. The present invention also provides a memory cell wherein the control gate (54) is smaller than the floating gate (52), and spacers (81) are present next to the control gate (54).

Fig. 10

Consistent with an example embodiment, there is a method of manufacturing on a substrate a 2-transistor memory cell comprising a storage transistor having a memory gate stack and a selecting transistor, there being a tunnel dielectric layer between the substrate and the memory gate stack. The method comprises forming the memory gate stack by providing a first conductive layer and a second conductive layer. The second conductive layer is etched thus forming a control gate; the first conductive layer and etching the first conductive layer thus forming a floating gate. The method further includes, before the first conductive layer is etched, spacers that are formed against the control gate in the direction of a channel to be formed under the tunnel dielectric layer. Thereafter using the spacers as a hard mask, the first conductive layer is etched thus forming the floating gate and making the floating gate self aligned with the control gate.